

Rochester Electronics Manufactured Components

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Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

74F182

Carry Lookahead Generator

General Description

The 74F182 is a high-speed carry lookahead generator. It is generally used with the 74F181 or 74F381 4-bit arithmetic logic units to provide high-speed lookahead over word lengths of more than four bits.

Features

- Provides lookahead carries across a group of four ALUs
- Multi-level lookahead high-speed arithmetic operation over long word lengths

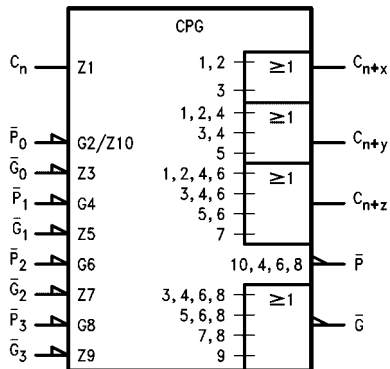
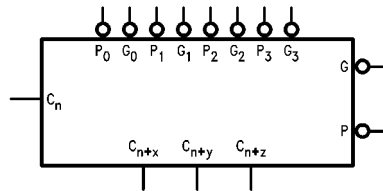
Ordering Code:

Order Number	Package Number	Package Description
74F182SJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F182PC (Note 1)	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

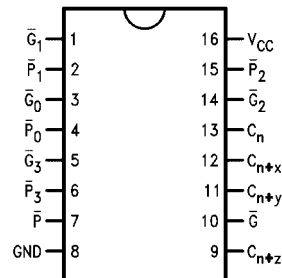
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Note 1: This device not available in Tape and Reel.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

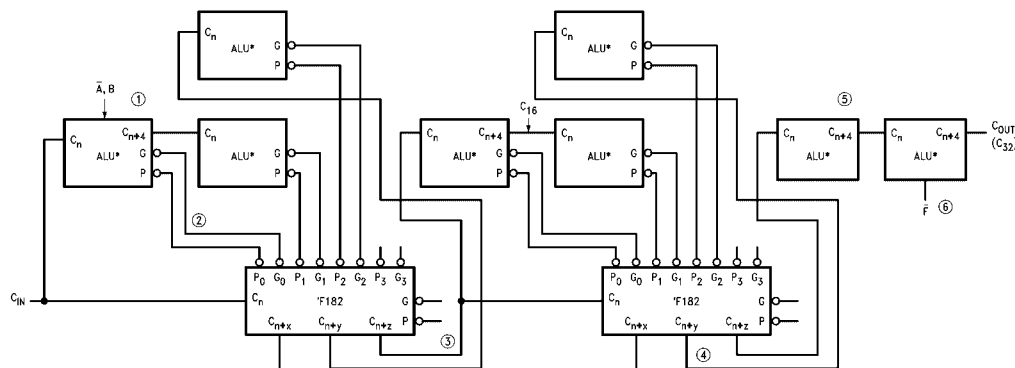
Pin Names	Description	U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
C_n	Carry Input	1.0/2.0	20 μ A/-1.2 mA
$\overline{G}_0, \overline{G}_2$	Carry Generate Inputs (Active LOW)	1.0/14.0	20 μ A/-8.4 mA
$\overline{G}_1$	Carry Generate Input (Active LOW)	1.0/16.0	20 μ A/-9.6 mA
$\overline{G}_3$	Carry Generate Input (Active LOW)	1.0/8.0	20 μ A/-4.8 mA
$\overline{P}_0, \overline{P}_1$	Carry Propagate Inputs (Active LOW)	1.0/8.0	20 μ A/-4.8 mA
$\overline{P}_2$	Carry Propagate Input (Active LOW)	1.0/6.0	20 μ A/-3.6 mA
$\overline{P}_3$	Carry Propagate Input (Active LOW)	1.0/4.0	20 μ A/-2.4 mA
$C_{n+x} - C_{n+z}$	Carry Outputs	50/33.3	-1 mA/20 mA
$\overline{G}$	Carry Generate Output (Active LOW)	50/33.3	-1 mA/20 mA
$\overline{P}$	Carry Propagate Output (Active LOW)	50/33.3	-1 mA/20 mA

Functional Description

The 74F182 carry lookahead generator accepts up to four pairs of Active LOW Carry Propagate ($\overline{P}_0$ - $\overline{P}_3$) and Carry Generate ($\overline{G}_0$ - $\overline{G}_3$) signals and an Active HIGH Carry input (C_n) and provides anticipated Active HIGH carries (C_{n+x} , C_{n+y} , C_{n+z}) across four groups of binary adders. The 74F182 also has Active LOW Carry Propagate ($\overline{P}$) and Carry Generate ($\overline{G}$) outputs which may be used for further levels of lookahead. The logic equations provided at the outputs are:

$$\begin{aligned}
 C_{n+x} &= G_0 + P_0 C_n \\
 C_{n+y} &= G_1 + P_1 G_0 + P_1 P_0 C_n \\
 C_{n+z} &= G_2 + P_2 G_1 + P_2 P_1 G_0 + P_2 P_1 P_0 C_n \\
 G &= \overline{G}_3 + \overline{P}_3 \overline{G}_2 + \overline{P}_3 \overline{P}_2 \overline{G}_1 + \overline{P}_3 \overline{P}_2 \overline{P}_1 \overline{G}_0 \\
 P &= \overline{P}_2 \overline{P}_1 \overline{P}_0
 \end{aligned}$$

Also, the 74F182 can be used with binary ALUs in an active LOW or active HIGH input operand mode. The connections (Figure 1) to and from the ALU to the carry lookahead generator are identical in both cases. Carries are rippled between lookahead blocks. The critical speed path follows the circled numbers. There are several possible arrangements for the carry interconnects, but all achieve about the same speed. A 28-bit ALU is formed by dropping the last 74F182 or 74F381.



*ALUs may be either 74F181 or 74F381

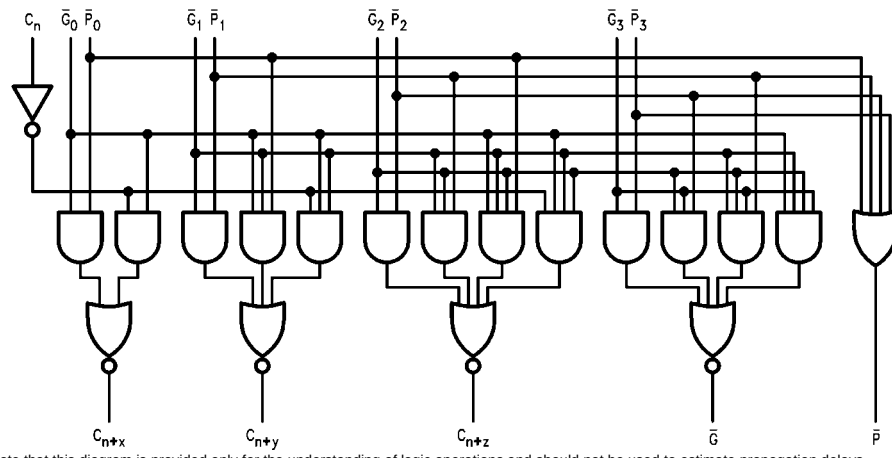
FIGURE 1. 32-Bit ALU with Rippled Carry between 16-Bit Lookahead ALUs

Truth Table

Inputs									Outputs				
C_n	$\overline{G}_0$	$\overline{P}_0$	$\overline{G}_1$	$\overline{P}_1$	$\overline{G}_2$	$\overline{P}_2$	$\overline{G}_3$	$\overline{P}_3$	C_{n+x}	C_{n+y}	C_{n+z}	$\overline{G}$	$\overline{P}$
X	H	H							L				
L	H	X							L				
X	L	X							H				
H	X	L							H				
X	X	X	H	H						L			
X	H	H	H	X						L			
L	H	X	H	X						L			
X	X	X	L	X						H			
X	L	X	X	L						H			
H	X	L	X	L						H			
X	X	X	X	X	H	H					L		
X	X	X	H	H	H	X					L		
X	H	H	H	X	H	X					L		
L	H	X	H	X	H	X					L		
X	X	X	X	X	L	X					H		
X	X	X	L	X	X	L					H		
X	L	X	X	L	X	L					H		
H	X	L	X	L	X	L					H		
			X	X	X	X	H	H				H	
			X	X	H	H	H	X				H	
			H	H	H	X	H	X				H	
			H	X	H	X	H	X				H	
			X	X	X	X	L	X				L	
			X	X	L	X	X	L				L	
			X	X	X	L	X	L				L	
			L	X	X	L	X	L				L	
		H		X		X		X					H
		X		H		X		X					H
		X		X		H		X					H
		X		X		X		H					H
		L		L		L		L					L

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 2)

Storage Temperature	–65°C to +150°C
Ambient Temperature under Bias	–55°C to +125°C
Junction Temperature under Bias	–55°C to +150°C
V _{CC} Pin Potential to Ground Pin	–0.5V to +7.0V
Input Voltage (Note 3)	–0.5V to +7.0V
Input Current (Note 3)	–30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with V _{CC} = 0V)	
Standard Output	–0.5V to V _{CC}
3-STATE Output	–0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated I _{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

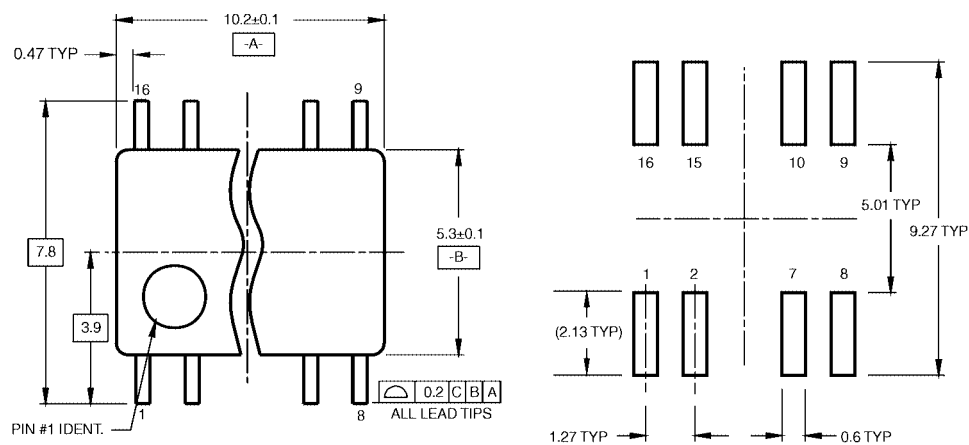
DC Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage			–1.2	V	Min	I _{IN} = –18 mA
V _{OH}	Output HIGH Voltage	10% V _{CC} 5% V _{CC}	2.5 2.7		V	Min	I _{OH} = –1 mA I _{OH} = –1 mA
V _{OL}	Output LOW Voltage	10% V _{CC}		0.5	V	Min	I _{OL} = 20 mA
I _{IH}	Input HIGH Current			5.0	μA	Max	V _{IN} = 2.7V
I _{BVI}	Input HIGH Current Breakdown Test			7.0	μA	Max	V _{IN} = 7.0V
I _{CEX}	Output HIGH Leakage Current			50	μA	Max	V _{OUT} = V _{CC}
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA All Other Pins Grounded
I _{OD}	Output Leakage Circuit Current			3.75	μA	0.0	V _{IOD} = 150 mV All Other Pins Grounded
I _{IL}	Input LOW Current			–1.2 –2.4 –3.6 –4.8 –8.4 –9.6	mA	Max	V _{IN} = 0.5V (C _n) V _{IN} = 0.5V ($\bar{P}_3$) V _{IN} = 0.5V ($\bar{P}_2$) V _{IN} = 0.5V ($\bar{G}_3, \bar{P}_0, \bar{P}_1$) V _{IN} = 0.5V ($\bar{G}_0, \bar{G}_2$) V _{IN} = 0.5V ($\bar{G}_1$)
I _{OS}	Output Short-Circuit Current	–60		–150	mA	Max	V _{OUT} = 0V
I _{CCH}	Power Supply Current		18.4	28.0	mA	Max	V _O = HIGH
I _{CCL}	Power Supply Current		23.5	36.0	mA	Max	V _O = LOW

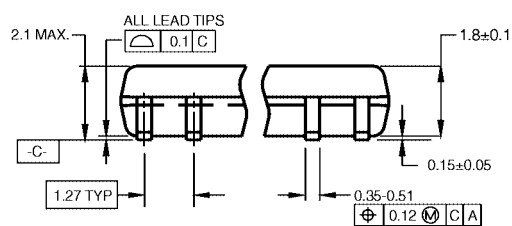
AC Electrical Characteristics

Symbol	Parameter	T _A = +25°C V _{CC} = +5.0V C _L = 50 pF			T _A = -55°C to +125°C V _{CC} = +5.0V C _L = 50 pF		T _A = 0°C to +70°C V _{CC} = +5.0V C _L = 50 pF		Units
		Min	Typ	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	3.0	6.6	8.5	3.0	12.0	3.0	9.5	ns
t _{PHL}	C _n to C _{n+x} , C _{n+y} , C _{n+z}	3.0	6.8	9.0	3.0	11.0	3.0	10.0	
t _{PLH}	Propagation Delay	2.5	6.2	8.0	2.5	11.0	2.5	9.0	ns
t _{PHL}	$\overline{P}_0$, $\overline{P}_1$, or $\overline{P}_2$ to C _{n+x} , C _{n+y} , or C _{n+z}	1.5	3.7	5.0	1.0	7.0	1.5	6.0	
t _{PLH}	Propagation Delay	2.5	6.5	8.5	2.5	11.0	2.5	9.5	ns
t _{PHL}	$\overline{G}_0$, $\overline{G}_1$, or $\overline{G}_2$ to C _{n+x} , C _{n+y} , or C _{n+z}	1.5	3.9	5.2	1.0	7.0	1.5	6.0	
t _{PLH}	Propagation Delay	3.0	7.9	10.0	3.0	12.0	3.0	11.0	ns
t _{PHL}	$\overline{P}_1$, $\overline{P}_2$, or $\overline{P}_3$ to $\overline{G}$	3.0	6.0	8.0	2.5	10.0	3.0	9.0	
t _{PLH}	Propagation Delay	3.0	8.3	10.5	3.0	12.0	3.0	11.5	ns
t _{PHL}	$\overline{G}_n$ to $\overline{G}$	3.0	5.7	7.5	2.5	10.0	3.0	8.5	
t _{PLH}	Propagation Delay	3.0	5.7	7.5	2.5	10.0	3.0	8.5	ns
t _{PHL}	$\overline{P}_n$ to $\overline{P}$	2.5	4.1	5.5	2.5	8.0	2.5	6.5	

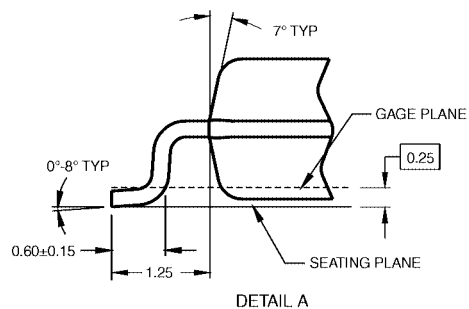
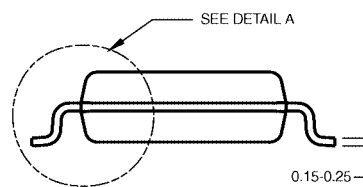
Physical Dimensions inches (millimeters) unless otherwise noted



LAND PATTERN RECOMMENDATION



DIMENSIONS ARE IN MILLIMETERS



DETAIL A

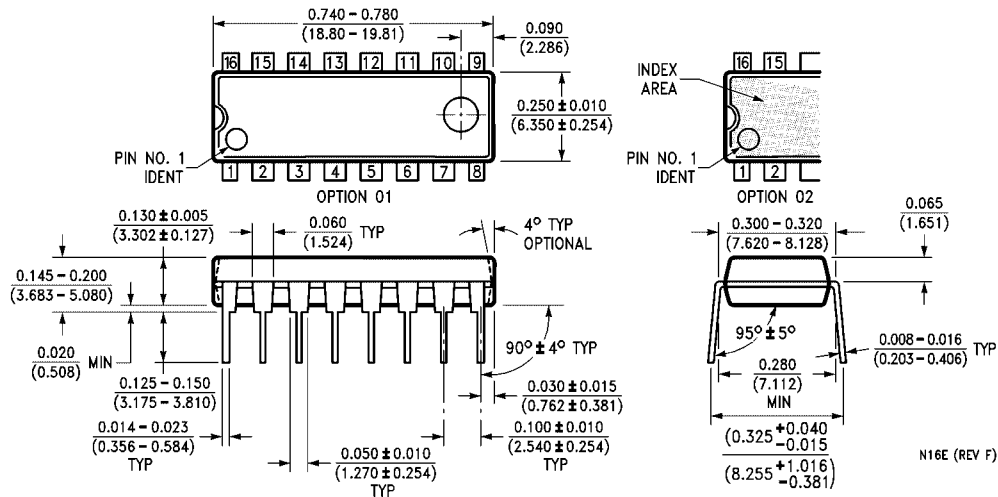
NOTES:

- A. CONFORMS TO EIAJ EDR-7320 REGISTRATION, ESTABLISHED IN DECEMBER, 1998.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

M16DRevB1

16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M16D

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
Package Number N16E

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2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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